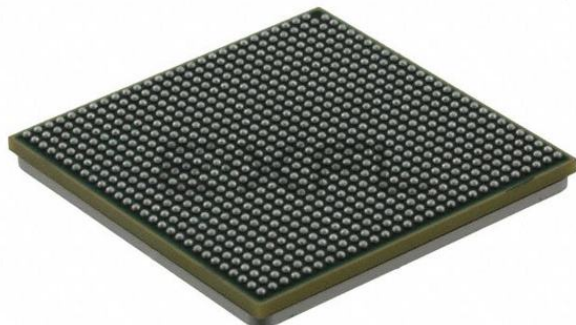




Welcome to [E-XFL.COM](#)

Understanding [Embedded - Microprocessors](#)

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of [Embedded - Microprocessors](#)

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

Product Status	Obsolete
Core Processor	PowerPC e500
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	800MHz
Co-Processors/DSP	Signal Processing; SPE
RAM Controllers	DDR, DDR2, SDRAM
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (4)
SATA	-
USB	-
Voltage - I/O	1.8V, 2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	-
Package / Case	783-BBGA, FCBGA
Supplier Device Package	783-FCBGA (29x29)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mpc8545vuang

NOTE

From a system standpoint, if any of the I/O power supplies ramp prior to the V_{DD} core supply, the I/Os associated with that I/O supply may drive a logic one or zero during power-up, and extra current may be drawn by the device.

Table 13 provides the recommended operating conditions for the DDR SDRAM controller when $GV_{DD}(\text{typ}) = 2.5 \text{ V}$.

Table 13. DDR SDRAM DC Electrical Characteristics for $GV_{DD}(\text{typ}) = 2.5 \text{ V}$

Parameter/Condition	Symbol	Min	Max	Unit	Notes
I/O supply voltage	GV_{DD}	2.375	2.625	V	1
I/O reference voltage	MV_{REF}	$0.49 \times GV_{DD}$	$0.51 \times GV_{DD}$	V	2
I/O termination voltage	V_{TT}	$MV_{REF} - 0.04$	$MV_{REF} + 0.04$	V	3
Input high voltage	V_{IH}	$MV_{REF} + 0.15$	$GV_{DD} + 0.3$	V	—
Input low voltage	V_{IL}	-0.3	$MV_{REF} - 0.15$	V	—
Output leakage current	I_{OZ}	-50	50	μA	4
Output high current ($V_{OUT} = 1.95 \text{ V}$)	I_{OH}	-16.2	—	mA	—
Output low current ($V_{OUT} = 0.35 \text{ V}$)	I_{OL}	16.2	—	mA	—

Notes:

1. GV_{DD} is expected to be within 50 mV of the DRAM V_{DD} at all times.
2. MV_{REF} is expected to be equal to $0.5 \times GV_{DD}$, and to track GV_{DD} DC variations as measured at the receiver. Peak-to-peak noise on MV_{REF} may not exceed $\pm 2\%$ of the DC value.
3. V_{TT} is not applied directly to the device. It is the supply to which far end signal termination is made and is expected to be equal to MV_{REF} . This rail must track variations in the DC level of MV_{REF} .
4. Output leakage is measured with all outputs disabled, $0 \text{ V} \leq V_{OUT} \leq GV_{DD}$.

Table 14 provides the DDR I/O capacitance when $GV_{DD}(\text{typ}) = 2.5 \text{ V}$.

Table 14. DDR SDRAM Capacitance for $GV_{DD}(\text{typ}) = 2.5 \text{ V}$

Parameter/Condition	Symbol	Min	Max	Unit	Notes
Input/output capacitance: DQ, DQS	C_{IO}	6	8	pF	1
Delta input/output capacitance: DQ, DQS	C_{DIO}	—	0.5	pF	1

Note:

1. This parameter is sampled. $GV_{DD} = 2.5 \text{ V} \pm 0.125 \text{ V}$, $f = 1 \text{ MHz}$, $T_A = 25^\circ\text{C}$, $V_{OUT} = GV_{DD}/2$, V_{OUT} (peak-to-peak) = 0.2 V.

This table provides the current draw characteristics for MV_{REF} .

Table 15. Current Draw Characteristics for MV_{REF}

Parameter/Condition	Symbol	Min	Max	Unit	Notes
Current draw for MV_{REF}	I_{MVREF}	—	500	μA	1

Note:

1. The voltage regulator for MV_{REF} must be able to supply up to 500 μA current.

Figure 11 shows the MII transmit AC timing diagram.

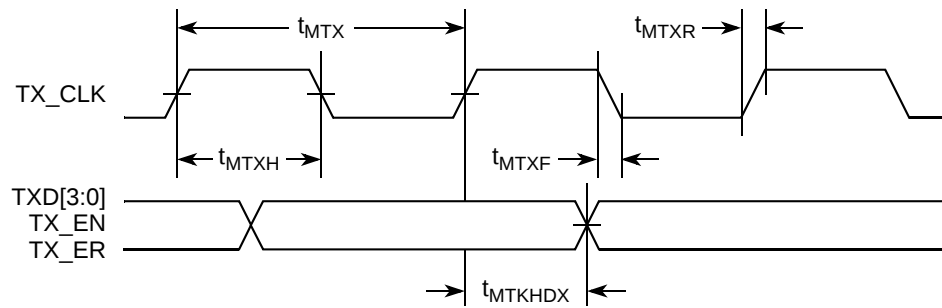


Figure 11. MII Transmit AC Timing Diagram

8.2.3.2 MII Receive AC Timing Specifications

This table provides the MII receive AC timing specifications.

Table 29. MII Receive AC Timing Specifications

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit
RX_CLK clock period 10 Mbps	t_{MRX}^2	—	400	—	ns
RX_CLK clock period 100 Mbps	t_{MRX}	—	40	—	ns
RX_CLK duty cycle	t_{MRXH}/t_{MRX}	35	—	65	%
RXD[3:0], RX_DV, RX_ER setup time to RX_CLK	t_{MRDVKH}	10.0	—	—	ns
RXD[3:0], RX_DV, RX_ER hold time to RX_CLK	t_{MRDXKH}	10.0	—	—	ns
RX_CLK clock rise (20%–80%)	t_{MRXR}^2	1.0	—	4.0	ns
RX_CLK clock fall time (80%–20%)	t_{MRXF}^2	1.0	—	4.0	ns

Notes:

- The symbols used for timing specifications follow the pattern of $t_{(\text{first two letters of functional block})(\text{signal})(\text{state})(\text{reference})(\text{state})}$ for inputs and $t_{(\text{first two letters of functional block})(\text{reference})(\text{state})(\text{signal})(\text{state})}$ for outputs. For example, t_{MRDVKH} symbolizes MII receive timing (MR) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{MRX} clock reference (K) going to the high (H) state or setup time. Also, t_{MRDXKL} symbolizes MII receive timing (GR) with respect to the time data input signals (D) went invalid (X) relative to the t_{MRX} clock reference (K) going to the low (L) state or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{MRX} represents the MII (M) receive (RX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
- Guaranteed by design.

Figure 12 provides the AC test load for eTSEC.

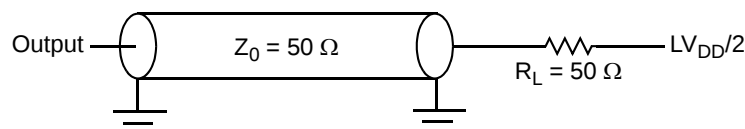


Figure 12. eTSEC AC Test Load

Figure 13 shows the MII receive AC timing diagram.

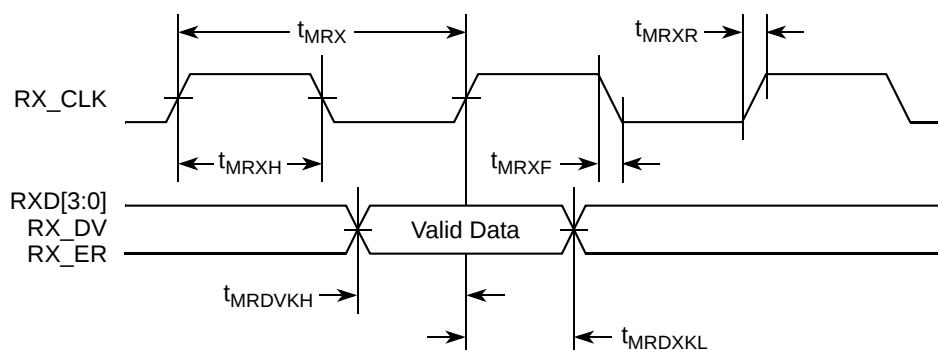


Figure 13. MII Receive AC Timing Diagram

8.2.4 TBI AC Timing Specifications

This section describes the TBI transmit and receive AC timing specifications.

8.2.4.1 TBI Transmit AC Timing Specifications

This table provides the TBI transmit AC timing specifications.

Table 30. TBI Transmit AC Timing Specifications

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit
TCG[9:0] setup time GTX_CLK going high	t_{TTKHDV}	2.0	—	—	ns
TCG[9:0] hold time from GTX_CLK going high	t_{TTKHDX}	1.0	—	—	ns
GTX_CLK rise (20%–80%)	t_{TTXR}^2	—	—	1.0	ns
GTX_CLK fall time (80%–20%)	t_{TTXF}^2	—	—	1.0	ns

Notes:

- The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{TTKHDV} symbolizes the TBI transmit timing (TT) with respect to the time from t_{TTX} (K) going high (H) until the referenced data signals (D) reach the valid state (V) or setup time. Also, t_{TTKHDX} symbolizes the TBI transmit timing (TT) with respect to the time from t_{TTX} (K) going high (H) until the referenced data signals (D) reach the invalid state (X) or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{TTX} represents the TBI (T) transmit (TX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
- Guaranteed by design.

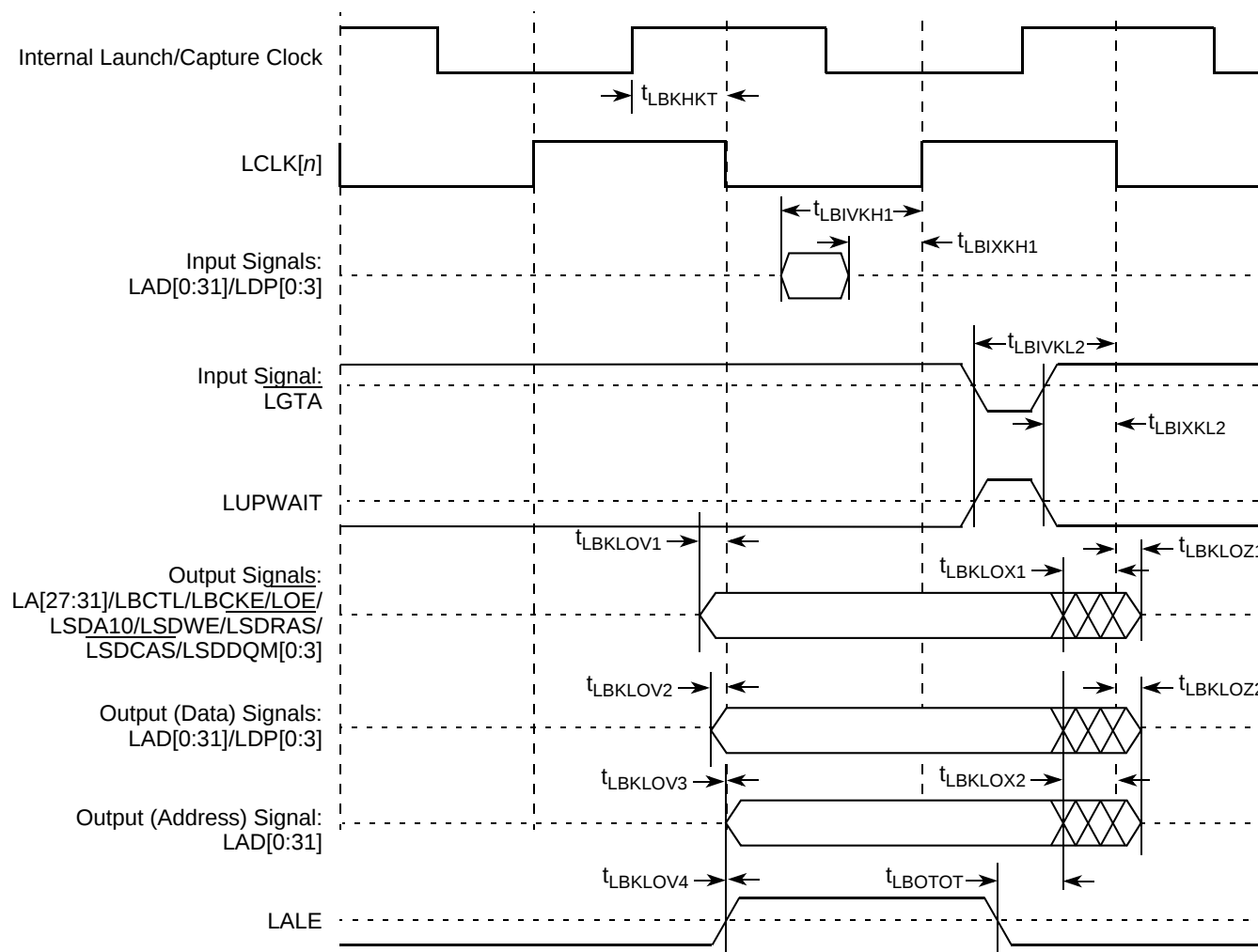


Figure 24. Local Bus Signals (PLL Bypass Mode)

NOTE

In PLL bypass mode, LCLK[n] is the inverted version of the internal clock with the delay of t_{LBKHK1} . In this mode, signals are launched at the rising edge of the internal clock and are captured at falling edge of the internal clock with the exception of $\overline{LGTA}$ /LUPWAIT (which is captured on the rising edge of the internal clock).

13 I²C

This section describes the DC and AC electrical characteristics for the I²C interfaces of the device.

13.1 I²C DC Electrical Characteristics

This table provides the DC electrical characteristics for the I²C interfaces.

Table 45. I²C DC Electrical Characteristics

Parameter	Symbol	Min	Max	Unit	Notes
Input high voltage level	V _{IH}	0.7 × OV _{DD}	OV _{DD} + 0.3	V	—
Input low voltage level	V _{IL}	−0.3	0.3 × OV _{DD}	V	—
Low level output voltage	V _{OL}	0	0.2 × OV _{DD}	V	1
Pulse width of spikes which must be suppressed by the input filter	t _{I2KHKL}	0	50	ns	2
Input current each I/O pin (input voltage is between 0.1 × OV _{DD} and 0.9 × OV _{DD} (max))	I _I	−10	10	μA	3
Capacitance for each I/O pin	C _I	—	10	pF	—

Notes:

1. Output voltage (open drain or open collector) condition = 3 mA sink current.
2. See the *MPC8548E PowerQUICC™ III Integrated Processor Family Reference Manual*, for information on the digital filter used.
3. I/O pins obstruct the SDA and SCL lines if OV_{DD} is switched off.

13.2 I²C AC Electrical Specifications

This table provides the AC timing parameters for the I²C interfaces.

Table 46. I²C AC Electrical Specifications

Parameter	Symbol ¹	Min	Max	Unit	Notes
SCL clock frequency	f _{I2C}	0	400	kHz	—
Low period of the SCL clock	t _{I2CL}	1.3	—	μs	4
High period of the SCL clock	t _{I2CH}	0.6	—	μs	4
Setup time for a repeated START condition	t _{I2SVKH}	0.6	—	μs	4
Hold time (repeated) START condition (after this period, the first clock pulse is generated)	t _{I2SXKL}	0.6	—	μs	4
Data setup time	t _{I2DVKH}	100	—	ns	4
Data input hold time: CBUS compatible masters I ² C bus devices	t _{I2DXKL}	— 0	— —	μs	2
Data output delay time:	t _{I2OVKL}	—	0.9	—	3
Set-up time for STOP condition	t _{I2PVKH}	0.6	—	μs	—
Bus free time between a STOP and START condition	t _{I2KHDX}	1.3	—	μs	—

Table 50. GP_{IN} DC Electrical Characteristics (2.5 V DC)

Parameter	Symbol	Min	Max	Unit
Supply voltage 2.5 V	BV _{DD}	2.37	2.63	V
High-level input voltage	V _{IH}	1.70	BV _{DD} + 0.3	V
Low-level input voltage	V _{IL}	−0.3	0.7	V
Input current (BV _{IN} ¹ = 0 V or BV _{IN} = BV _{DD})	I _{IH}	—	10	μA

Note:

1. The symbol BV_{IN}, in this case, represents the BV_{IN} symbol referenced in [Table 1](#).

15 PCI/PCI-X

This section describes the DC and AC electrical specifications for the PCI/PCI-X bus of the device. Note that the maximum PCI-X frequency in synchronous mode is 110 MHz.

15.1 PCI/PCI-X DC Electrical Characteristics

This table provides the DC electrical characteristics for the PCI/PCI-X interface.

Table 51. PCI/PCI-X DC Electrical Characteristics¹

Parameter	Symbol	Min	Max	Unit	Notes
High-level input voltage	V _{IH}	2	OV _{DD} + 0.3	V	—
Low-level input voltage	V _{IL}	−0.3	0.8	V	—
Input current (V _{IN} = 0 V or V _{IN} = V _{DD})	I _{IN}	—	±5	μA	2
High-level output voltage (OV _{DD} = min, I _{OH} = −2 mA)	V _{OH}	2.4	—	V	—
Low-level output voltage (OV _{DD} = min, I _{OL} = 2 mA)	V _{OL}	—	0.4	V	—

Notes:

1. Ranges listed do not meet the full range of the DC specifications of the *PCI 2.2 Local Bus Specifications*.
2. The symbol V_{IN}, in this case, represents the OV_{IN} symbol referenced in [Table 1](#) and [Table 2](#).

15.2 PCI/PCI-X AC Electrical Specifications

This section describes the general AC timing parameters of the PCI/PCI-X bus. Note that the clock reference CLK is represented by SYSCLK when the PCI controller is configured for synchronous mode and by PCIn_CLK when it is configured for asynchronous mode.

of a balanced interchange circuit and ground. In this example, for SerDes output, $V_{cm_out} = V_{SD_TX} + V_{\overline{SD_TX}} = (A + B)/2$, which is the arithmetic mean of the two complimentary output voltages within a differential pair. In a system, the common mode voltage may often differ from one component's output to the other's input. Sometimes, it may be even different between the receiver input and driver output circuits within the same component. It is also referred to as the DC offset.

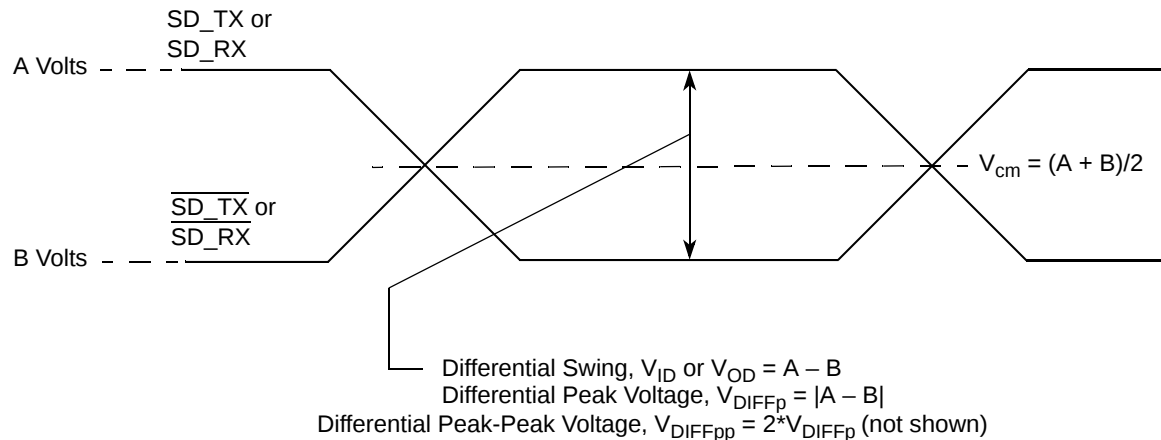


Figure 38. Differential Voltage Definitions for Transmitter or Receiver

To illustrate these definitions using real values, consider the case of a CML (current mode logic) transmitter that has a common mode voltage of 2.25 V and each of its outputs, TD and $\overline{TD}$, has a swing that goes between 2.5 and 2.0 V. Using these values, the peak-to-peak voltage swing of each signal (TD or $\overline{TD}$) is 500 mVp-p, which is referred to as the single-ended swing for each signal. In this example, since the differential signaling environment is fully symmetrical, the transmitter output's differential swing (V_{OD}) has the same amplitude as each signal's single-ended swing. The differential output signal ranges between 500 and -500 mV, in other words, V_{OD} is 500 mV in one phase and -500 mV in the other phase. The peak differential voltage (V_{DIFFp}) is 500 mV. The peak-to-peak differential voltage (V_{DIFFpp}) is 1000 mVp-p.

16.2 SerDes Reference Clocks

The SerDes reference clock inputs are applied to an internal PLL whose output creates the clock used by the corresponding SerDes lanes. The SerDes reference clocks inputs are SD_REF_CLK and $\overline{SD_REF_CLK}$ for PCI Express and serial RapidIO.

The following sections describe the SerDes reference clock requirements and some application information.

16.2.1 SerDes Reference Clock Receiver Characteristics

Figure 39 shows a receiver reference diagram of the SerDes reference clocks.

- The supply voltage requirements for XV_{DD_SRDS2} are specified in Table 1 and Table 2.
- SerDes Reference clock receiver reference circuit structure:

Table 57. Differential Receiver (RX) Input Specifications (continued)

Symbol	Parameter	Min	Nom	Max	Unit	Comments
$V_{RX-CM-ACp}$	AC peak common mode input voltage	—	—	150	mV	$V_{RX-CM-ACp} = V_{RXD+} - V_{RXD-} /2 + V_{RX-CM-DC}$ $V_{RX-CM-DC} = DC_{(avg)} \text{ of } V_{RX-D+} + V_{RX-D-} \div 2$. See Note 2.
$RL_{RX-DIFF}$	Differential return loss	15	—	—	dB	Measured over 50 MHz to 1.25 GHz with the D+ and D– lines biased at +300 mV and –300 mV, respectively. See Note 4.
RL_{RX-CM}	Common mode return loss	6	—	—	dB	Measured over 50 MHz to 1.25 GHz with the D+ and D– lines biased at 0 V. See Note 4.
$Z_{RX-DIFF-DC}$	DC differential input impedance	80	100	120	Ω	RX DC differential mode impedance. See Note 5.
Z_{RX-DC}	DC input impedance	40	50	60	Ω	Required RX D+ as well as D– DC impedance ($50 \pm 20\%$ tolerance). See Notes 2 and 5.
$Z_{RX-HIGH-IMP-DC}$	Powered down DC input impedance	200 k	—	—	Ω	Required RX D+ as well as D– DC impedance when the receiver terminations do not have power. See Note 6.
$V_{RX-IDLE-DET-DIFFp-p}$	Electrical idle detect threshold	65	—	175	mV	$V_{RX-IDLE-DET-DIFFp-p} = 2 \times V_{RX-D+} - V_{RX-D-} $. Measured at the package pins of the receiver
$T_{RX-IDLE-DET-DIFF-ENTERTIME}$	Unexpected electrical idle enter detect threshold integration time	—	—	10	ms	An unexpected electrical idle ($V_{RX-DIFFp-p} < V_{RX-IDLE-DET-DIFFp-p}$) must be recognized no longer than $T_{RX-IDLE-DET-DIFF-ENTERING}$ to signal an unexpected idle condition.

Table 63. Long Run Transmitter AC Timing Specifications—2.5 GBaud

Characteristic	Symbol	Range		Unit	Notes
		Min	Max		
Output voltage	V_O	-0.40	2.30	V	Voltage relative to COMMON of either signal comprising a differential pair
Differential output voltage	V_{DIFFPP}	800	1600	mVp-p	—
Deterministic jitter	J_D	—	0.17	UI p-p	—
Total jitter	J_T	—	0.35	UI p-p	—
Multiple output skew	S_{MO}	—	1000	ps	Skew at the transmitter output between lanes of a multilane link
Unit interval	UI	400	400	ps	±100 ppm

Table 64. Long Run Transmitter AC Timing Specifications—3.125 GBaud

Characteristic	Symbol	Range		Unit	Notes
		Min	Max		
Output voltage	V_O	-0.40	2.30	V	Voltage relative to COMMON of either signal comprising a differential pair
Differential output voltage	V_{DIFFPP}	800	1600	mVp-p	—
Deterministic jitter	J_D	—	0.17	UI p-p	—
Total jitter	J_T	—	0.35	UI p-p	—
Multiple output skew	S_{MO}	—	1000	ps	Skew at the transmitter output between lanes of a multilane link
Unit interval	UI	320	320	ps	±100 ppm

For each baud rate at which an LP-serial transmitter is specified to operate, the output eye pattern of the transmitter shall fall entirely within the unshaded portion of the transmitter output compliance mask shown in [Figure 52](#) with the parameters specified in [Table 65](#) when measured at the output pins of the device and the device is driving a $100\text{-}\Omega \pm 5\%$ differential resistive load. The output eye pattern of an LP-serial

transmitter that implements pre-emphasis (to equalize the link and reduce inter-symbol interference) need only comply with the transmitter output compliance mask when pre-emphasis is disabled or minimized.

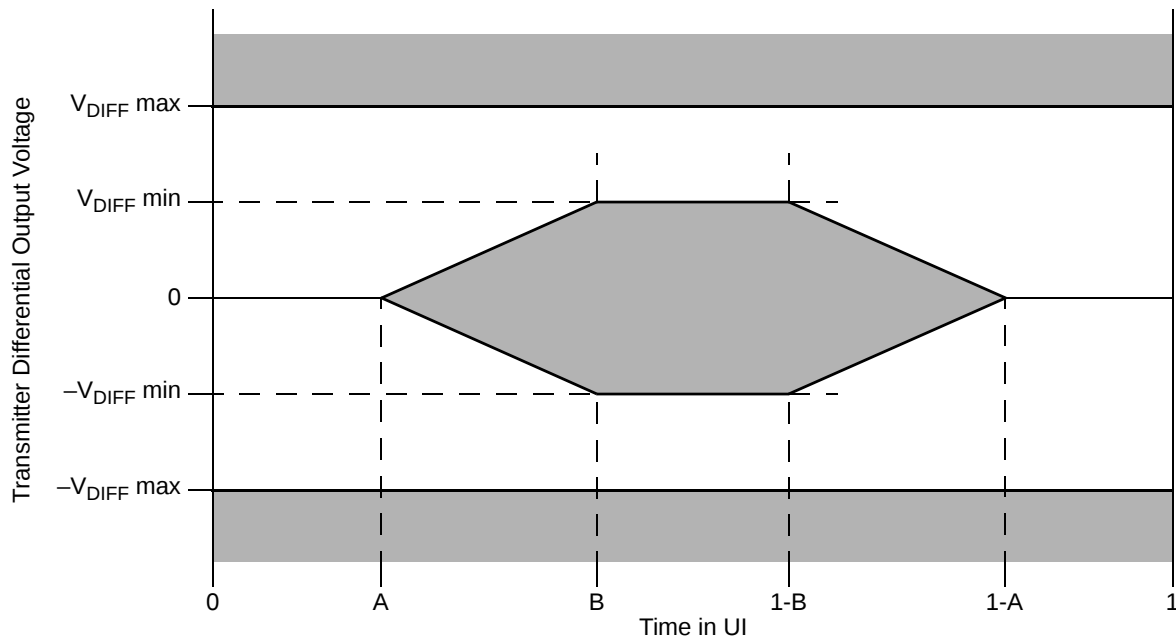


Figure 52. Transmitter Output Compliance Mask

Table 65. Transmitter Differential Output Eye Diagram Parameters

Transmitter Type	$V_{DIFFmin}$ (mV)	$V_{DIFFmax}$ (mV)	A (UI)	B (UI)
1.25 GBaud short range	250	500	0.175	0.39
1.25 GBaud long range	400	800	0.175	0.39
2.5 GBaud short range	250	500	0.175	0.39
2.5 GBaud long range	400	800	0.175	0.39
3.125 GBaud short range	250	500	0.175	0.39
3.125 GBaud long range	400	800	0.175	0.39

18.7 Receiver Specifications

LP-serial receiver electrical and timing specifications are stated in the text and tables of this section.

Receiver input impedance shall result in a differential return loss better than 10 dB and a common mode return loss better than 6 dB from 100 MHz to $(0.8) \times$ (baud frequency). This includes contributions from on-chip circuitry, the chip package, and any off-chip components related to the receiver. AC coupling

802.3ae-2002 is specified as the test pattern for use in eye pattern and jitter measurements. Annex 48B of IEEE Std. 802.3ae-2002 is recommended as a reference for additional information on jitter test methods.

18.9.1 Eye Template Measurements

For the purpose of eye template measurements, the effects of a single-pole high pass filter with a 3 dB point at (baud frequency)/1667 is applied to the jitter. The data pattern for template measurements is the continuous jitter test pattern (CJPAT) defined in Annex 48A of IEEE 802.3ae. All lanes of the LP-serial link shall be active in both the transmit and receive directions, and opposite ends of the links shall use asynchronous clocks. Four lane implementations shall use CJPAT as defined in Annex 48A. Single lane implementations shall use the CJPAT sequence specified in Annex 48A for transmission on lane 0. The amount of data represented in the eye shall be adequate to ensure that the bit error ratio is less than 10^{-12} . The eye pattern shall be measured with AC coupling and the compliance template centered at 0 V differential. The left and right edges of the template shall be aligned with the mean zero crossing points of the measured data eye. The load for this test shall be 100- Ω resistive $\pm$ 5% differential to 2.5 GHz.

18.9.2 Jitter Test Measurements

For the purpose of jitter measurement, the effects of a single-pole high pass filter with a 3 dB point at (baud frequency)/1667 is applied to the jitter. The data pattern for jitter measurements is the Continuous Jitter test pattern (CJPAT) pattern defined in Annex 48A of IEEE 802.3ae. All lanes of the LP-serial link shall be active in both the transmit and receive directions, and opposite ends of the links shall use asynchronous clocks. Four lane implementations shall use CJPAT as defined in Annex 48A. Single lane implementations shall use the CJPAT sequence specified in Annex 48A for transmission on lane 0. Jitter shall be measured with AC coupling and at 0 V differential. Jitter measurement for the transmitter (or for calibration of a jitter tolerance setup) shall be performed with a test procedure resulting in a BER curve such as that described in Annex 48B of IEEE 802.3ae.

18.9.3 Transmit Jitter

Transmit jitter is measured at the driver output when terminated into a load of 100 Ω resistive $\pm$ 5% differential to 2.5 GHz.

18.9.4 Jitter Tolerance

Jitter tolerance is measured at the receiver using a jitter tolerance test signal. This signal is obtained by first producing the sum of deterministic and random jitter defined in [Section 18.7, “Receiver Specifications,”](#) and then adjusting the signal amplitude until the data eye contacts the 6 points of the minimum eye opening of the receive template shown in [Figure 54](#) and [Table 69](#). Note that for this to occur, the test signal must have vertical waveform symmetry about the average value and have horizontal symmetry (including jitter) about the mean zero crossing. Eye template measurement requirements are as defined above. Random jitter is calibrated using a high pass filter with a low frequency corner at 20 MHz and a 20 dB/decade roll-off below this. The required sinusoidal jitter specified in [Section 18.7, “Receiver Specifications,”](#) is then added to the signal and the test load is replaced by the receiver being tested.

19.2 Mechanical Dimensions of the HiCTE FC-CBGA and FC-PBGA with Full Lid

The following figures show the mechanical dimensions and bottom surface nomenclature for the MPC8548E HiCTE FC-CBGA and FC-PBGA packages.

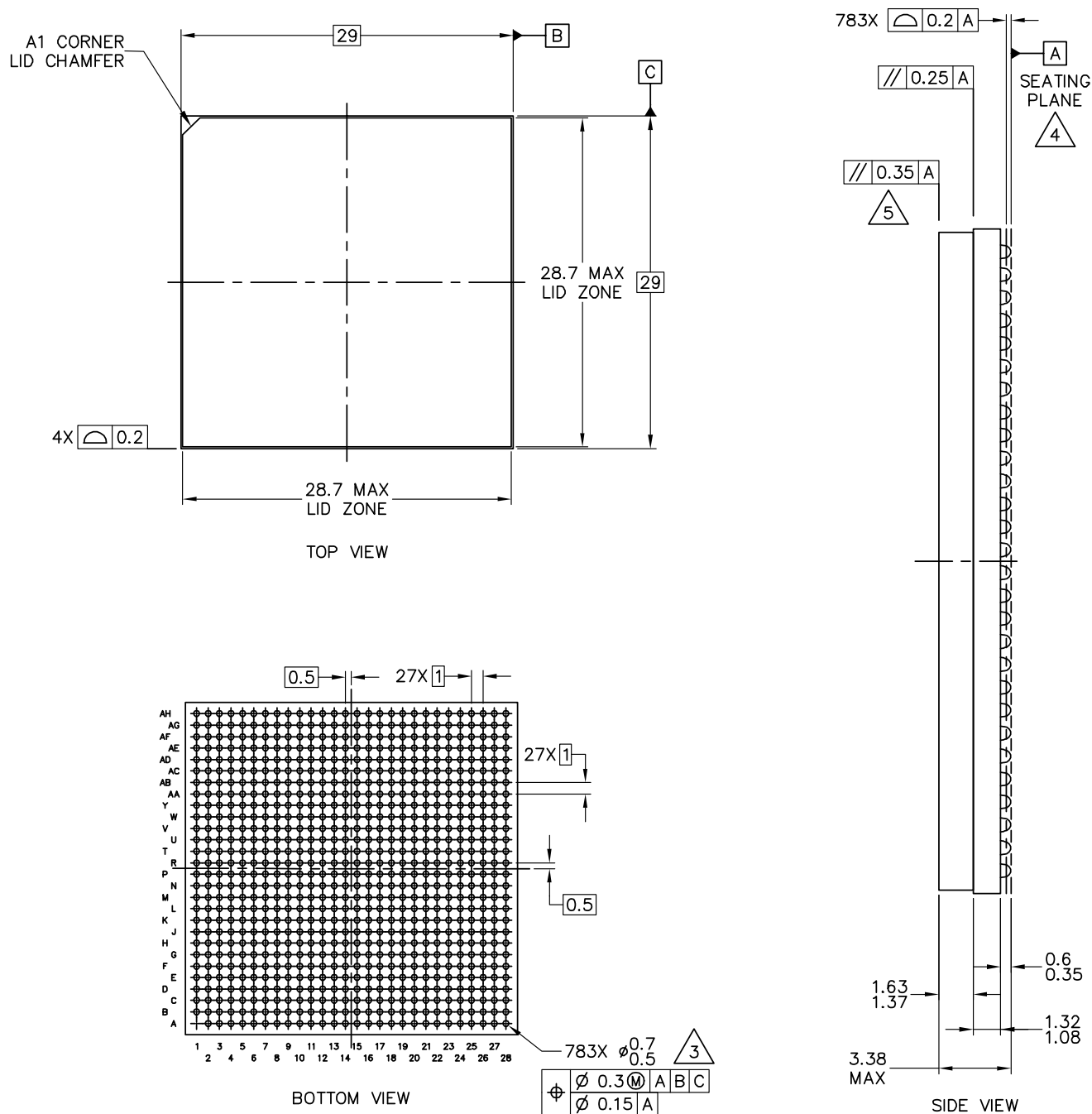


Figure 55. Mechanical Dimensions and Bottom Surface Nomenclature of the HiCTE FC-CBGA and FC-PBGA with Full Lid

Table 71. MPC8548E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
$\overline{\text{PCI1_REQ}}[4:1]$	AH2, AG4, AG3, AH4	I	OV_{DD}	—
				—
				—
				—
				—
$\overline{\text{PCI1_REQ0}}$	AH3	I/O	OV_{DD}	—
$\overline{\text{PCI1_CLK}}$	AH26	I	OV_{DD}	39
$\overline{\text{PCI1_DEVSEL}}$	AH11	I/O	OV_{DD}	2
$\overline{\text{PCI1_FRAME}}$	AE11	I/O	OV_{DD}	2
$\overline{\text{PCI1_IDSEL}}$	AG9	I	OV_{DD}	—
$\overline{\text{PCI1_REQ64/PCI2_FRAME}}$	AF14	I/O	OV_{DD}	2, 5, 10
$\overline{\text{PCI1_ACK64/PCI2_DEVSEL}}$	V15	I/O	OV_{DD}	2
$\overline{\text{PCI2_CLK}}$	AE28	I	OV_{DD}	39
$\overline{\text{PCI2_IRDY}}$	AD26	I/O	OV_{DD}	2
$\overline{\text{PCI2_PERR}}$	AD25	I/O	OV_{DD}	2
$\overline{\text{PCI2_GNT}}[4:1]$	AE26, AG24, AF25, AE25	O	OV_{DD}	5, 9, 35
$\overline{\text{PCI2_GNT0}}$	AG25	I/O	OV_{DD}	—
$\overline{\text{PCI2_SERR}}$	AD24	I/O	OV_{DD}	2, 4
$\overline{\text{PCI2_STOP}}$	AF24	I/O	OV_{DD}	2
$\overline{\text{PCI2_TRDY}}$	AD27	I/O	OV_{DD}	2
$\overline{\text{PCI2_REQ}}[4:1]$	AD28, AE27, W17, AF26	I	OV_{DD}	—
$\overline{\text{PCI2_REQ0}}$	AH25	I/O	OV_{DD}	—
DDR SDRAM Memory Interface				
MDQ[0:63]	L18, J18, K14, L13, L19, M18, L15, L14, A17, B17, A13, B12, C18, B18, B13, A12, H18, F18, J14, F15, K19, J19, H16, K15, D17, G16, K13, D14, D18, F17, F14, E14, A7, A6, D5, A4, C8, D7, B5, B4, A2, B1, D1, E4, A3, B2, D2, E3, F3, G4, J5, K5, F6, G5, J6, K4, J1, K2, M5, M3, J3, J2, L1, M6	I/O	GV_{DD}	—
MECC[0:7]	H13, F13, F11, C11, J13, G13, D12, M12	I/O	GV_{DD}	—
MDM[0:8]	M17, C16, K17, E16, B6, C4, H4, K1, E13	O	GV_{DD}	—
MDQS[0:8]	M15, A16, G17, G14, A5, D3, H1, L2, C13	I/O	GV_{DD}	—
$\overline{\text{MDQS}}[0:8]$	L17, B16, J16, H14, C6, C2, H3, L4, D13	I/O	GV_{DD}	—
MA[0:15]	A8, F9, D9, B9, A9, L10, M10, H10, K10, G10, B8, E10, B10, G6, A10, L11	O	GV_{DD}	—
MBA[0:2]	F7, J7, M11	O	GV_{DD}	—

Table 71. MPC8548E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
$\overline{\text{MWE}}$	E7	O	GV _{DD}	—
$\overline{\text{MCAS}}$	H7	O	GV _{DD}	—
$\overline{\text{MRAS}}$	L8	O	GV _{DD}	—
MCKE[0:3]	F10, C10, J11, H11	O	GV _{DD}	11
$\overline{\text{MCS}}[0:3]$	K8, J8, G8, F8	O	GV _{DD}	—
MCK[0:5]	H9, B15, G2, M9, A14, F1	O	GV _{DD}	—
$\overline{\text{MCK}}[0:5]$	J9, A15, G1, L9, B14, F2	O	GV _{DD}	—
MODT[0:3]	E6, K6, L7, M7	O	GV _{DD}	—
MDIC[0:1]	A19, B19	I/O	GV _{DD}	36
Local Bus Controller Interface				
LAD[0:31]	E27, B20, H19, F25, A20, C19, E28, J23, A25, K22, B28, D27, D19, J22, K20, D28, D25, B25, E22, F22, F21, C25, C22, B23, F20, A23, A22, E19, A21, D21, F19, B21	I/O	BV _{DD}	—
LDP[0:3]	K21, C28, B26, B22	I/O	BV _{DD}	—
LA[27]	H21	O	BV _{DD}	5, 9
LA[28:31]	H20, A27, D26, A28	O	BV _{DD}	5, 7, 9
$\overline{\text{LCS}}[0:4]$	J25, C20, J24, G26, A26	O	BV _{DD}	
$\overline{\text{LCS5/DMA_DREQ2}}$	D23	I/O	BV _{DD}	1
$\overline{\text{LCS6/DMA_DACK2}}$	G20	O	BV _{DD}	1
$\overline{\text{LCS7/DMA_DDONE2}}$	E21	O	BV _{DD}	1
$\overline{\text{LWE0/LBS0/LSDDQM}}[0]$	G25	O	BV _{DD}	5, 9
$\overline{\text{LWE1/LBS1/LSDDQM}}[1]$	C23	O	BV _{DD}	5, 9
$\overline{\text{LWE2/LBS2/LSDDQM}}[2]$	J21	O	BV _{DD}	5, 9
$\overline{\text{LWE3/LBS3/LSDDQM}}[3]$	A24	O	BV _{DD}	5, 9
LAL	H24	O	BV _{DD}	5, 8, 9
LBCTL	G27	O	BV _{DD}	5, 8, 9
LGPL0/LSDA10	F23	O	BV _{DD}	5, 9
LGPL1/LSDWE	G22	O	BV _{DD}	5, 9
LGPL2/ $\overline{\text{LOE/LSDRAS}}$	B27	O	BV _{DD}	5, 8, 9
LGPL3/ $\overline{\text{LSDCAS}}$	F24	O	BV _{DD}	5, 9
LGPL4/ $\overline{\text{LGT\AA/LUPWAIT/LPBSE}}$	H23	I/O	BV _{DD}	—
LGPL5	E26	O	BV _{DD}	5, 9
LCKE	E24	O	BV _{DD}	—
LCLK[0:2]	E23, D24, H22	O	BV _{DD}	—

Table 71. MPC8548E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
LSYNC_IN	F27	I	BV _{DD}	—
LSYNC_OUT	F28	O	BV _{DD}	—
DMA				
DMA_DACK[0:1]	AD3, AE1	O	OV _{DD}	5, 9, 102
DMA_DREQ[0:1]	AD4, AE2	I	OV _{DD}	—
DMA_DDONE[0:1]	AD2, AD1	O	OV _{DD}	—
Programmable Interrupt Controller				
UDE	AH16	I	OV _{DD}	—
MCP	AG19	I	OV _{DD}	—
IRQ[0:7]	AG23, AF18, AE18, AF20, AG18, AF17, AH24, AE20	I	OV _{DD}	—
IRQ[8]	AF19	I	OV _{DD}	—
IRQ[9]/DMA_DREQ3	AF21	I	OV _{DD}	1
IRQ[10]/DMA_DACK3	AE19	I/O	OV _{DD}	1
IRQ[11]/DMA_DDONE3	AD20	I/O	OV _{DD}	1
IRQ_OUT	AD18	O	OV _{DD}	2, 4
Ethernet Management Interface				
EC_MDC	AB9	O	OV _{DD}	5, 9
EC_MDIO	AC8	I/O	OV _{DD}	—
Gigabit Reference Clock				
EC_GTX_CLK125	V11	I	LV _{DD}	—
Three-Speed Ethernet Controller (Gigabit Ethernet 1)				
TSEC1_RXD[7:0]	R5, U1, R3, U2, V3, V1, T3, T2	I	LV _{DD}	—
TSEC1_TXD[7:0]	T10, V7, U10, U5, U4, V6, T5, T8	O	LV _{DD}	5, 9
TSEC1_COL	R4	I	LV _{DD}	—
TSEC1_CRS	V5	I/O	LV _{DD}	20
TSEC1_GTX_CLK	U7	O	LV _{DD}	—
TSEC1_RX_CLK	U3	I	LV _{DD}	—
TSEC1_RX_DV	V2	I	LV _{DD}	—
TSEC1_RX_ER	T1	I	LV _{DD}	—
TSEC1_TX_CLK	T6	I	LV _{DD}	—
TSEC1_TX_EN	U9	O	LV _{DD}	30
TSEC1_TX_ER	T7	O	LV _{DD}	—

Table 72. MPC8547E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
Local Bus Controller Interface				
LAD[0:31]	E27, B20, H19, F25, A20, C19, E28, J23, A25, K22, B28, D27, D19, J22, K20, D28, D25, B25, E22, F22, F21, C25, C22, B23, F20, A23, A22, E19, A21, D21, F19, B21	I/O	BV _{DD}	—
LDP[0:3]	K21, C28, B26, B22	I/O	BV _{DD}	—
LA[27]	H21	O	BV _{DD}	5, 9
LA[28:31]	H20, A27, D26, A28	O	BV _{DD}	5, 7, 9
$\overline{\text{LCS}}[0:4]$	J25, C20, J24, G26, A26	O	BV _{DD}	—
$\overline{\text{LCS5/DMA_DREQ2}}$	D23	I/O	BV _{DD}	1
$\overline{\text{LCS6/DMA_DACK2}}$	G20	O	BV _{DD}	1
$\overline{\text{LCS7/DMA_DDONE2}}$	E21	O	BV _{DD}	1
$\overline{\text{LWE0/LBS0/LSDDQM}}[0]$	G25	O	BV _{DD}	5, 9
$\overline{\text{LWE1/LBS1/LSDDQM}}[1]$	C23	O	BV _{DD}	5, 9
$\overline{\text{LWE2/LBS2/LSDDQM}}[2]$	J21	O	BV _{DD}	5, 9
$\overline{\text{LWE3/LBS3/LSDDQM}}[3]$	A24	O	BV _{DD}	5, 9
LALE	H24	O	BV _{DD}	5, 8, 9
LBCTL	G27	O	BV _{DD}	5, 8, 9
LGPL0/LSDA10	F23	O	BV _{DD}	5, 9
LGPL1/ $\overline{\text{LSDWE}}$	G22	O	BV _{DD}	5, 9
LGPL2/ $\overline{\text{LOE/LSDRAS}}$	B27	O	BV _{DD}	5, 8, 9
LGPL3/ $\overline{\text{LSDCAS}}$	F24	O	BV _{DD}	5, 9
LGPL4/ $\overline{\text{LGT\AA/LUPWAIT/LPBSE}}$	H23	I/O	BV _{DD}	—
LGPL5	E26	O	BV _{DD}	5, 9
LCKE	E24	O	BV _{DD}	—
LCLK[0:2]	E23, D24, H22	O	BV _{DD}	—
LSYNC_IN	F27	I	BV _{DD}	—
LSYNC_OUT	F28	O	BV _{DD}	—
DMA				
$\overline{\text{DMA_DACK}}[0:1]$	AD3, AE1	O	OV _{DD}	5, 9, 107
$\overline{\text{DMA_DREQ}}[0:1]$	AD4, AE2	I	OV _{DD}	—
$\overline{\text{DMA_DDONE}}[0:1]$	AD2, AD1	O	OV _{DD}	—
Programmable Interrupt Controller				
$\overline{\text{UDE}}$	AH16	I	OV _{DD}	—
$\overline{\text{MCP}}$	AG19	I	OV _{DD}	—

level must always be equivalent to V_{DD} , and preferably these voltages are derived directly from V_{DD} through a low frequency filter scheme such as the following.

There are a number of ways to reliably provide power to the PLLs, but the recommended solution is to provide independent filter circuits per PLL power supply as illustrated in Figure 57, one to each of the AV_{DD} pins. By providing independent filters to each PLL the opportunity to cause noise injection from one PLL to the other is reduced.

This circuit is intended to filter noise in the PLLs resonant frequency range from a 500 kHz to 10 MHz range. It must be built with surface mount capacitors with minimum Effective Series Inductance (ESL). Consistent with the recommendations of Dr. Howard Johnson in *High Speed Digital Design: A Handbook of Black Magic* (Prentice Hall, 1993), multiple small capacitors of equal value are recommended over a single large value capacitor.

Each circuit must be placed as close as possible to the specific AV_{DD} pin being supplied to minimize noise coupled from nearby circuits. It must be routed directly from the capacitors to the AV_{DD} pin, which is on the periphery of the footprint, without the inductance of vias.

Figure 57 through Figure 59 shows the PLL power supply filter circuits.

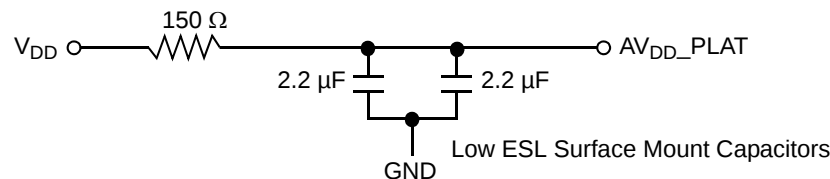


Figure 57. PLL Power Supply Filter Circuit with PLAT Pins

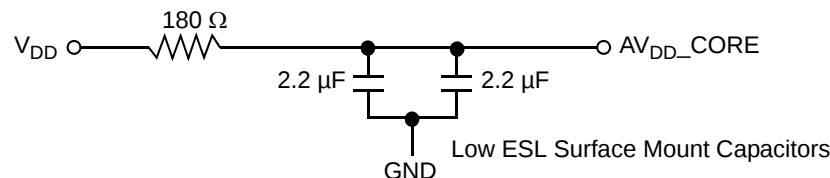


Figure 58. PLL Power Supply Filter Circuit with CORE Pins

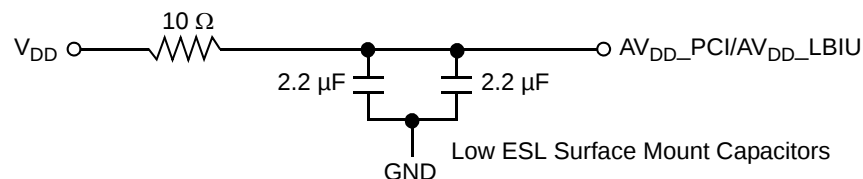
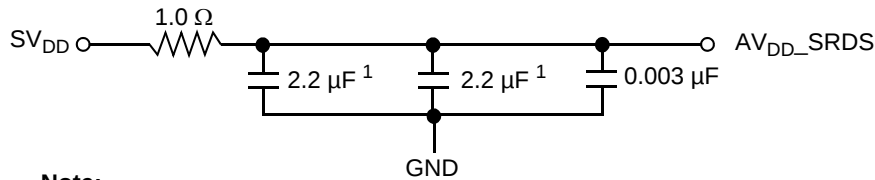


Figure 59. PLL Power Supply Filter Circuit with PCI/LBIU Pins

The AV_{DD_SRDS} signal provides power for the analog portions of the SerDes PLL. To ensure stability of the internal clock, the power supplied to the PLL is filtered using a circuit similar to the one shown in following figure. For maximum effectiveness, the filter circuit is placed as closely as possible to the AV_{DD_SRDS} ball to ensure it filters out as much noise as possible. The ground connection must be near the AV_{DD_SRDS} ball. The $0.003\text{-}\mu\text{F}$ capacitor is closest to the ball, followed by the two $2.2\ \mu\text{F}$ capacitors, and finally the $1\ \Omega$ resistor to the board supply plane. The capacitors are connected from AV_{DD_SRDS} to

the ground plane. Use ceramic chip capacitors with the highest possible self-resonant frequency. All traces must be kept short, wide and direct.



Note:

1. An 0805 sized capacitor is recommended for system initial bring-up.

Figure 60. SerDes PLL Power Supply Filter

Note the following:

- AV_{DD_SRDS} must be a filtered version of SV_{DD} .
- Signals on the SerDes interface are fed from the XV_{DD} power plane.

22.3 Decoupling Recommendations

Due to large address and data buses, and high operating frequencies, the device can generate transient power surges and high frequency noise in its power supply, especially while driving large capacitive loads. This noise must be prevented from reaching other components in the device system, and the device itself requires a clean, tightly regulated source of power. Therefore, it is recommended that the system designer place at least one decoupling capacitor at each V_{DD} , TV_{DD} , BV_{DD} , OV_{DD} , GV_{DD} , and LV_{DD} pin of the device. These decoupling capacitors must receive their power from separate V_{DD} , TV_{DD} , BV_{DD} , OV_{DD} , GV_{DD} , LV_{DD} , and GND power planes in the PCB, utilizing short low impedance traces to minimize inductance. Capacitors must be placed directly under the device using a standard escape pattern as much as possible. If some caps are to be placed surrounding the part it must be routed with large trace to minimize the inductance.

These capacitors must have a value of 0.1 μF . Only ceramic SMT (surface mount technology) capacitors must be used to minimize lead inductance, preferably 0402 or 0603 sizes. Besides, it is recommended that there be several bulk storage capacitors distributed around the PCB, feeding the V_{DD} , TV_{DD} , BV_{DD} , OV_{DD} , GV_{DD} , and LV_{DD} , planes, to enable quick recharging of the smaller chip capacitors. These bulk capacitors must have a low ESR (equivalent series resistance) rating to ensure the quick response time necessary. They must also be connected to the power and ground planes through two vias to minimize inductance. Suggested bulk capacitors—100–330 μF (AVX TPS tantalum or Sanyo OSCON). However, customers must work directly with their power regulator vendor for best values, types and quantity of bulk capacitors.

22.4 SerDes Block Power Supply Decoupling Recommendations

The SerDes block requires a clean, tightly regulated source of power (SV_{DD} and XV_{DD}) to ensure low jitter on transmit and reliable recovery of data in the receiver. An appropriate decoupling scheme is outlined below.

Only surface mount technology (SMT) capacitors must be used to minimize inductance. Connections from all capacitors to power and ground must be done with multiple vias to further reduce inductance.

How to Reach Us:

Home Page:

www.freescale.com

Web Support:

<http://www.freescale.com/support>

USA/Europe or Locations Not Listed:

Freescale Semiconductor, Inc.
Technical Information Center, EL516
2100 East Elliot Road
Tempe, Arizona 85284
1-800-521-6274 or +1-480-768-2130
www.freescale.com/support

Europe, Middle East, and Africa:

Freescale Halbleiter Deutschland GmbH
Technical Information Center
Schatzbogen 7
81829 Muenchen, Germany
+44 1296 380 456 (English)
+46 8 52200080 (English)
+49 89 92103 559 (German)
+33 1 69 35 48 48 (French)
www.freescale.com/support

Japan:

Freescale Semiconductor Japan Ltd.
Headquarters
ARCO Tower 15F
1-8-1, Shimo-Meguro, Meguro-ku,
Tokyo 153-0064
Japan
0120 191014 or +81 3 5437 9125
support.japan@freescale.com

Asia/Pacific:

Freescale Semiconductor China Ltd.
Exchange Building 23F
No. 118 Jianguo Road
Chaoyang District
Beijing 100022
China
+86 10 5879 8000
support.asia@freescale.com

Information in this document is provided solely to enable system and software implementers to use Freescale Semiconductor products. There are no express or implied copyright licenses granted hereunder to design or fabricate any integrated circuits or integrated circuits based on the information in this document.

Freescale Semiconductor reserves the right to make changes without further notice to any products herein. Freescale Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does Freescale Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation consequential or incidental damages. "Typical" parameters that may be provided in Freescale Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals", must be validated for each customer application by customer's technical experts. Freescale Semiconductor does not convey any license under its patent rights nor the rights of others. Freescale Semiconductor products are not designed, intended, or authorized for use as components in systems intended for surgical implant into the body, or other applications intended to support or sustain life, or for any other application in which the failure of the Freescale Semiconductor product could create a situation where personal injury or death may occur. Should Buyer purchase or use Freescale Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and hold Freescale Semiconductor and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that Freescale Semiconductor was negligent regarding the design or manufacture of the part.

Freescale, the Freescale logo, CodeWarrior, ColdFire, PowerQUICC, QorIQ, StarCore, and Symphony are trademarks of Freescale Semiconductor, Inc. Reg., U.S. Pat. & Tm. Off. CoreNet, QorIQ Qonverge, QUICC Engine, and VortiQa are trademarks of Freescale Semiconductor, Inc. All other product or service names are the property of their respective owners.

© 2012 Freescale Semiconductor, Inc.

